N-Channel Enhancement Mode Power MOSFET

General Description

The HM75N $\ddot{\text{I}}$ $\dot{\text{I}}$ S uses advanced trench technology and design to provide excellent R_{DS(ON)} with low gate charge. This device is suitable for use in PWM, load switching and general purpose applications.

Features

- V_{DS} =75V; I_D = \ddot{I} A@ V_{GS} =10V; $R_{DS(ON)}$ <Jm Ω @ V_{GS} =10V
- Special process technology for high ESD capability
- Special designed for Convertors and power controls
- High density cell design for ultra low Rdson
- Fully characterized Avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation

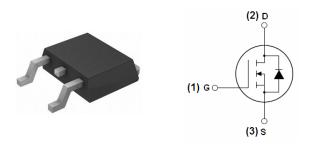
Application

- Power switching application
- Hard Switched and High Frequency Circuits
- Uninterruptible Power Supply

Product Summary

BV _{DSS} typ.	75	Х
R _{DS(ON)} typ.	7.0	mΩ
max.	9.0	mΩ
I _D	75	Α

100% UIS TESTED!



HC!&) & top viewGW Ya UrjWX]U[fUa

Package Marking And Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
HM75NÏÍSÁ‱WWWPTÏÍÞÏÍSÁ∭WWWWWVUËEÍG					-

Table 1. Absolute Maximum Ratings (TA=25℃)

Parameter	Symbol	Value	Unit
Drain-Source Voltage (V _{GS} =0V)	V _{DS}	75	V
Gate-Source Voltage (V _{DS} =0V)	V _{GS}	±25	V
Drain Current (DC) at Tc=25℃	I _{D (DC)}	ΪÍ	А
Drain Current (DC) at Tc=100°C	I _{D (DC)}	60	А
Drain Current-Continuous@ Current-Pulsed (Note 1)	I _{DM (pluse)}	300	А
Peak diode recovery voltage	dv/dt	30	V/ns
Maximum Power Dissipation(Tc=25℃)	P _D	170	W
Derating factor		1.13	W/℃
Single pulse avalanche energy (Note 2)	E _{AS}	580	mJ
Operating Junction and Storage Temperature Range	T_{J} , T_{STG}	-55 To 175	$^{\circ}$ C

Notes 1. Repetitive Rating: Pulse width limited by maximum junction temperature

2.EAS condition: Tj=25 $^{\circ}$ C,VDD=50V,VG=10V,L=0.3mH,ID=62A;

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Table 2. Thermal Characteristic

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case (Maximum)	R _{thJC}	0.88	°C/W
Thermal Resistance, Junction-to-Ambient (Maximum)	R _{thJA}	63	°C/W

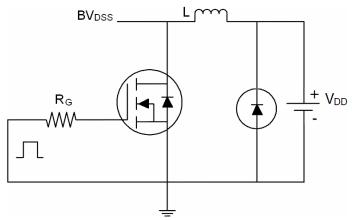
Table 3. Electrical Characteristics (TA=25℃ unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
On/off states						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250μA	75	84		V
Zero Gate Voltage Drain Current(Tc=25℃)	I _{DSS}	V _{DS} =75V,V _{GS} =0V			1	μΑ
Zero Gate Voltage Drain Current(Tc=125℃)	I _{DSS}	V _{DS} =75V,V _{GS} =0V			10	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V			±100	nA
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} ,I _D =250μA	2	2.85	4	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =40A	ÁXXX	XXXXX ȀXXX	XXXXXXXJ	mΩ
Dynamic Characteristics						
Forward Transconductance	G FS	V _{DS} =5V,I _D =30A		66		S
Input Capacitance	C _{lss}	\/ -05\/\/ -0\/		4400		PF
Output Capacitance	Coss	V_{DS} =25V, V_{GS} =0V, F=1.0MHz		340		PF
Reverse Transfer Capacitance	C _{rss}	F-1.UIVITZ		260		PF
Total Gate Charge	Qg	\/ -20\/ L -20 A		100		nC
Gate-Source Charge	Q _{gs}	V_{DS} =30V, I_{D} =30A, V_{GS} =10V		20		nC
Gate-Drain Charge	Q_{gd}	V _{GS} -10V		30		nC
Switching times						
Turn-on Delay Time	t _{d(on)}			17.8		nS
Turn-on Rise Time	t _r	V_{DD} =30 V , I_D =2 A , R_L =15 Ω		11.8		nS
Turn-Off Delay Time	t _{d(off)}	V_{GS} =10V, R_{G} =2.5 Ω		56		nS
Turn-Off Fall Time	t _f			14.6		nS
Source- Drain Diode Characteristics						
Source-drain current(Body Diode)	I _{SD}		/ 1 /***********************************		Α	
Pulsed Source-drain current(Body Diode)	I _{SDM}				320	Α
Forward on voltage ^(Note 1)	V _{SD}	Tj=25°C,I _{SD} =40A,V _{GS} =0V			1.2	V
Reverse Recovery Time ^(Note 1)	t _{rr}	Ti-25°C L -75A di/dt-100A/vo			36	nS
Reverse Recovery Charge ^(Note 1)	Q _{rr}	- Tj=25℃,I _F =75A,di/dt=100A/μs			56	nC
Forward Turn-on Time	t _{on}	Intrinsic turn-on time is negligible(turn-on is dominated by L _S +L _D)				

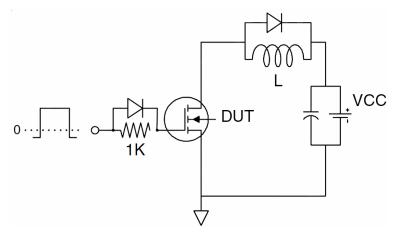
Notes 1.Pulse Test: Pulse Width ≤ 300 μ s, Duty Cycle ≤ 1.5%, R_G=25 Ω , Starting Tj=25 $^{\circ}$ C

Test circuit

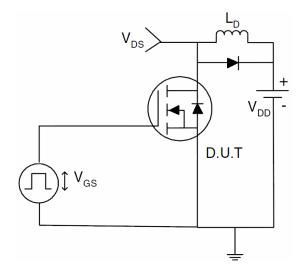
1) E_{AS} test circuits



2) Gate charge test circuit:



3) Switch Time Test Circuit:



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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS (curves)

Figure 1. Safe operating area

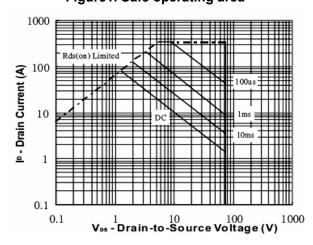


Figure 2. Source-Drain Diode Forward Voltage

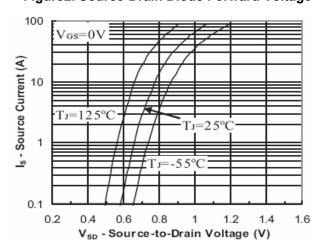


Figure 3. Output characteristics

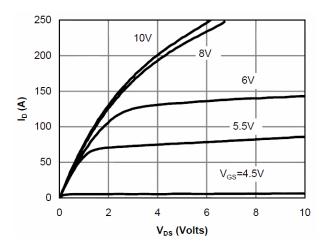


Figure 4. Transfer characteristics

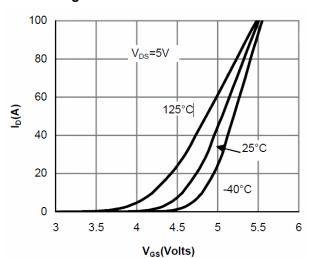


Figure 5. Static drain-source on resistance

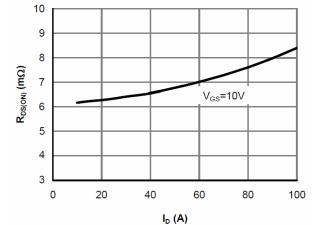
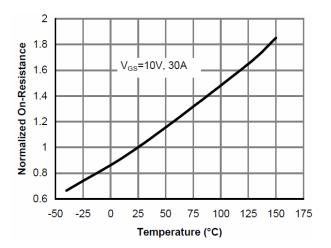


Figure 6. R_{DS(ON)} vs Junction Temperature



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Figure 7. BV_{DSS} vs Junction Temperature

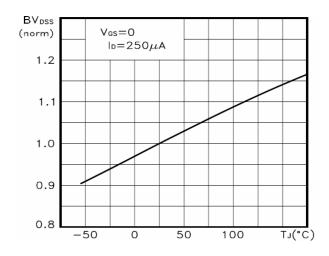


Figure 8. V_{GS(th)} vs Junction Temperature

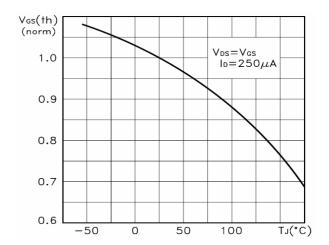


Figure 9. Gate charge waveforms

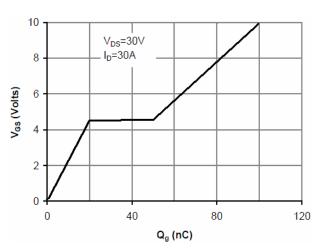
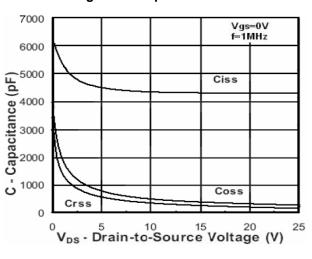
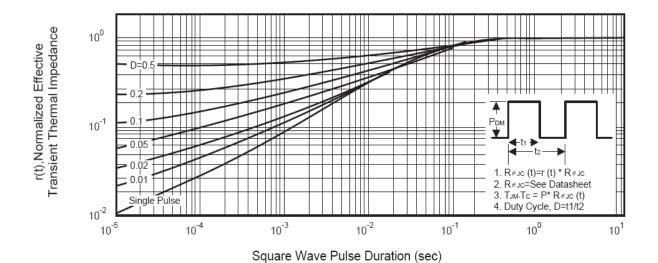


Figure 10. Capacitance

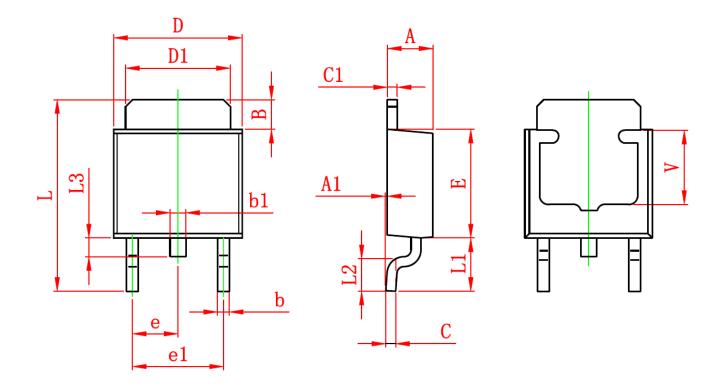




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TO-252-2L PACKAGE OUTLINE DIMENSIONS



Symbol	Dimensions	In Millimeters	Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
Α	2.200	2.400	0.087	0.094	
A1	0.000	0.127	0.000	0.005	
В	1.350	1.650	0.053	0.065	
b	0.500	0.700	0.020	0.028	
b1	0.700	0.900	0.028	0.035	
С	0.430	0.580	0.017	0.023	
c1	0.430	0.580	0.017	0.023	
D	6.350	6.650	0.250	0.262	
D1	5.200	5.400	0.205	0.213	
E	5.400	5.700	0.213	0.224	
е	2.300 TYP.		0.091 TYP.		
e1	4.500	4.700	0.177	0.185	
L	9.500	9.900	0.374	0.390	
L1	2.550	2.900	0.100	0.114	
L2	1.400	1.780	0.055	0.070	
L3	0.600	0.900	0.024	0.035	
V	3.800 REF.		0.150	REF.	

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